

ISU
DEPARTMENT OF ELECTRICAL ENGINEERING
and COMPUTER SCIENCE

S e m i n a r

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“ASIC Reliability”

Friday October 9, 2009, Room 7 LIBRARY

ISU Pocatello Campus

1:00 – 1:50 p.m.

Abstract:

Reliability requirements of Application Specific Integrated Circuits varies from cell phone and DVD player applications to Mars rovers, from implanted neurostimulators to industrial robots. IC reliability concepts such as intrinsic reliability, failure modes, wearout, extrinsic reliability, defects, reliability testing, and manufacturing monitor strategies will be discussed.